



**PATENT**

**DOCKET NO.: 1743/224**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANTS : Hideo TODOKORO, et al.  
SERIAL NO. : 10/648,388  
FILED : 27 August 2003  
FOR : SCANNING ELECTRON MICROSCOPE  
GROUP ART UNIT : 2881  
EXAMINER : David A. Vanore

COMMISSIONER FOR PATENTS  
P. O. Box 1450  
Alexandria, Virginia 22313-1450

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 C.F.R. § 1.97 & § 1.98**

S I R:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(c)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In accordance with the requirements of 37 C.F.R. § 1.98, copies of the references are submitted herewith.

**Statement of Relevancy**

The references were cited in an office action issued by the Japanese Patent Office in a counterpart Japanese application.

**Statement Pursuant to 37 CFR §1.97(c)(1) & (e)(1)**

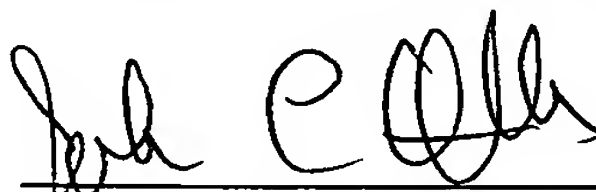
The undersigned attorney hereby states that each item of information contained in this information disclosure statement was first cited in any



communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'John C. Altmiller', written over a horizontal line.

John C. Altmiller  
(Reg. No. 25,951)

Date: 18 November 2004

KENYON & KENYON  
1500 K Street, N.W., Suite 700  
Washington, DC 20005

(202) 220-4200 Tel.  
(202) 220-4201 Fax



**FORM PTO-1449**  
**INFORMATION DISCLOSURE**  
**STATEMENT BY APPLICANT(S)**



Atty Docket No. : 1743/224  
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 Examiner : David A. Vanore

**U.S. PATENT DOCUMENTS**

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
	5,389,787	02/14/95	TODOKORO et al.	250/310	

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
	10-74478	03/17/98	Japan	= USP 5,389,787	ABS.
	07-014537	01/17/95	Japan		

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner  
Initial

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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.